

ヘテロ接合型結晶シリコン太陽電池におけるアモルファスシリコン界面層の物性と発電性能の相関

Effects of a-Si:H bilayers in a-Si:H/c-Si heterojunction solar cells

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Research Background

■ a-Si:H/c-Si heterojunction (SHJ) solar cells

- Excellent surface passivation by using a-Si:H [1]
- High efficiency (> 25%), high V_{OC} and low T-coefficient
- Suitable to bi-facial modules
- Applicable to thin wafers thanks to low-T process

■ Key issue – (i)a-Si:H/c-Si interface

□ Surface passivation

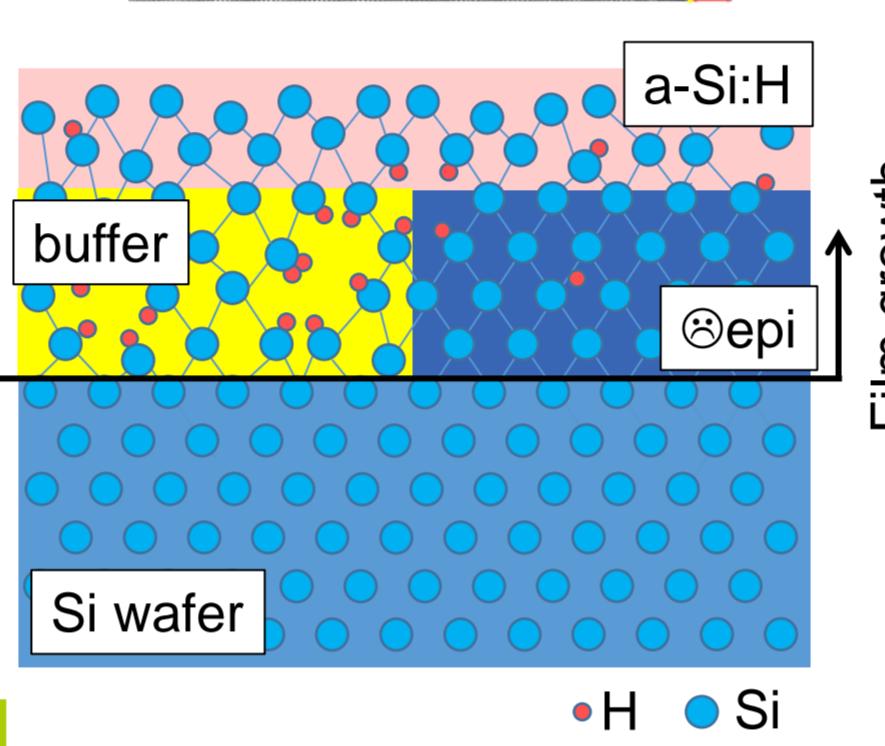
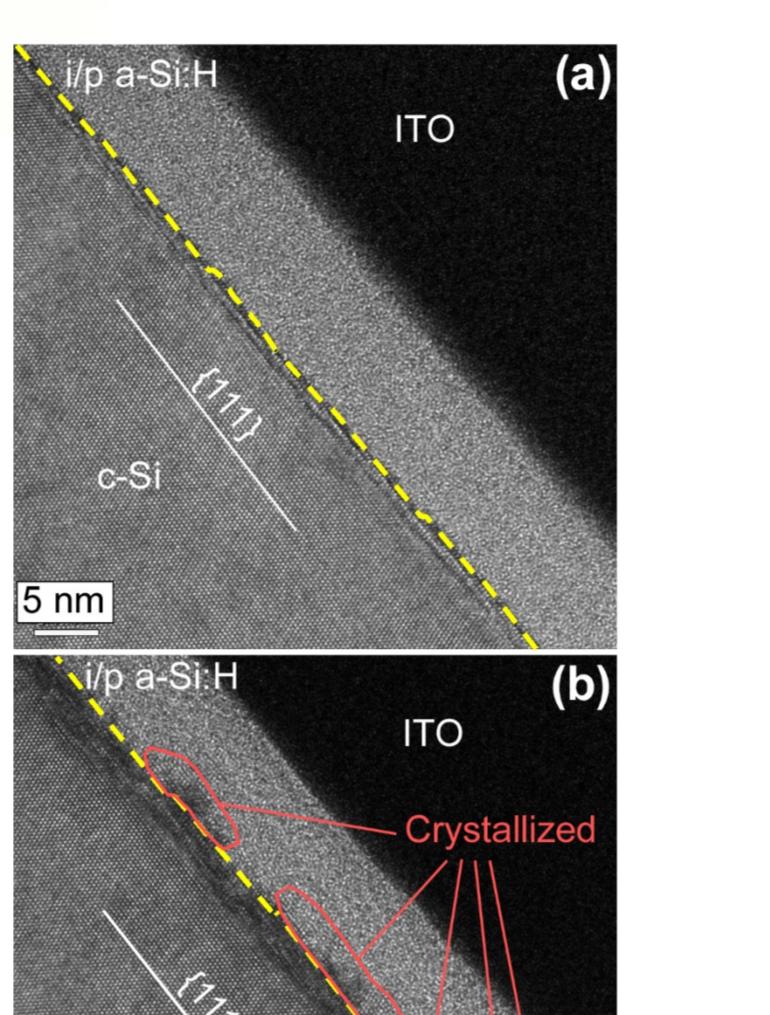
- Abrupt a-Si:H/c-Si interface is preferable. Epitaxial growth is detrimental (either as-grown or post-growth).
- Overlying p-layer deteriorates the passivation

□ Carrier transport channel

- Series resistance should be minimized.

■ 2-step growth of (i)a-Si:H [2-4]

- Interfacial layer (i_1) + bulk layer (i_2) is effective for improving surface passivation.
- Record-efficiency (25.1%) cell has been achieved.[4]



Experimental

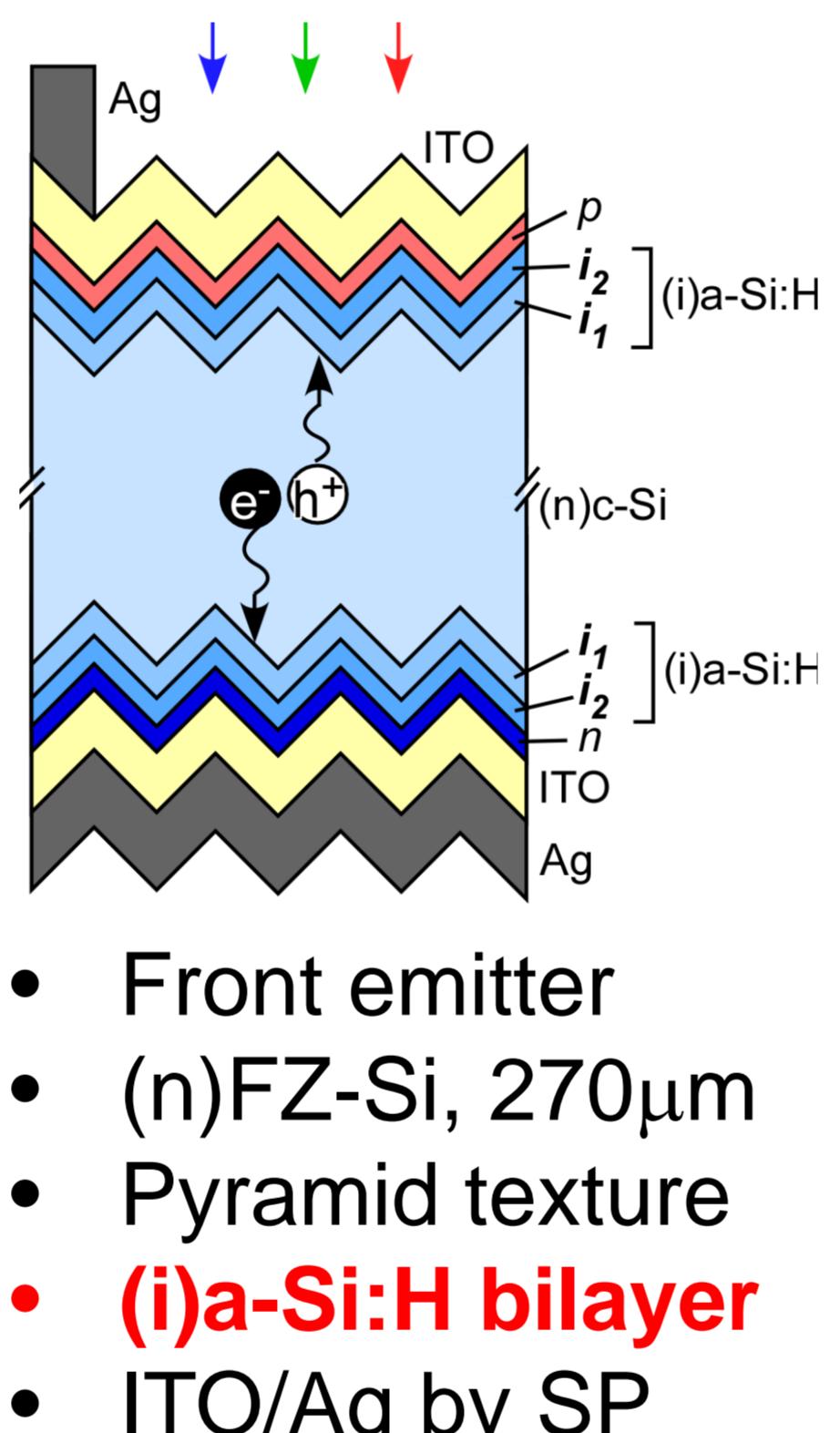
■ Growth of (i)a-Si:H layers

- PECVD, CCP, 13.56MHz
- Characterization: Ellipsometry, FT-IR

Table: Growth conditions for (i)a-Si:H layers

Layer Series		i_1	i_2
Si precursor	SiH_4 , Si_2H_6	SiH_4	SiH_4
Si_2H_6 concentration, $C_{\text{Si}_2\text{H}_6}$ [Si_2H_6]/[$(\text{SiH}_4 + \text{Si}_2\text{H}_6)$]	0 – 75%	0	0
Hydrogen dilution $[\text{H}_2]/[\text{SiH}_4]$	0	0	10
Substrate temperature, T_s (°C)	200	30 – 400	200
Pressure, P (Pa)	13, 40	13	13-40
Power density (mW cm ⁻²)	11	11	11

■ Solar cell

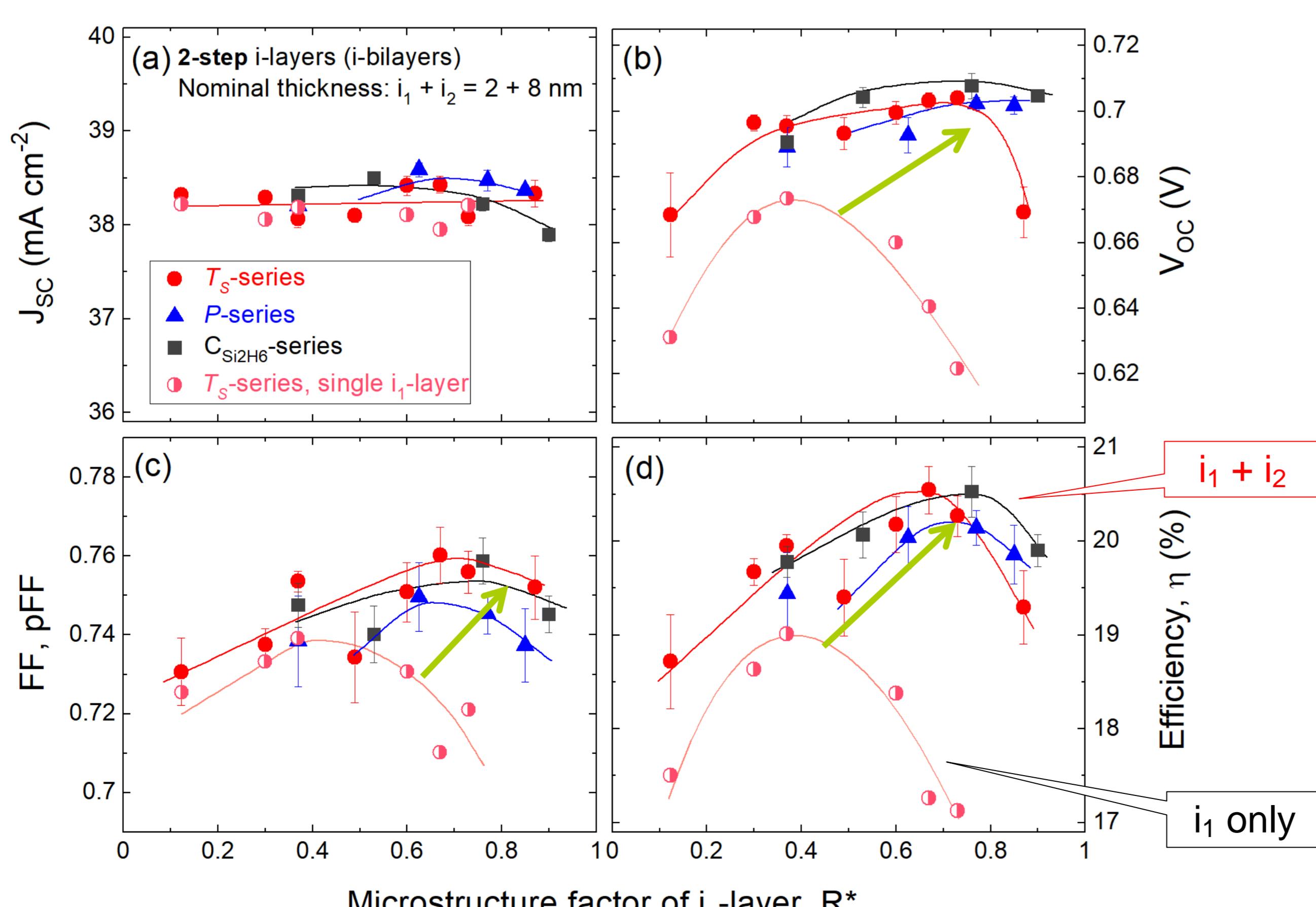


- Front emitter
- (n)FZ-Si, 270μm
- Pyramid texture
- (i)a-Si:H bilayer
- ITO/Ag by SP

SHJ cells with (i)a-Si:H bilayers ($i_1 + i_2$) [6]

■ Effect of (i)a-Si:H bilayer: i_1 - and i_2 -layers (2 + 8 nm)

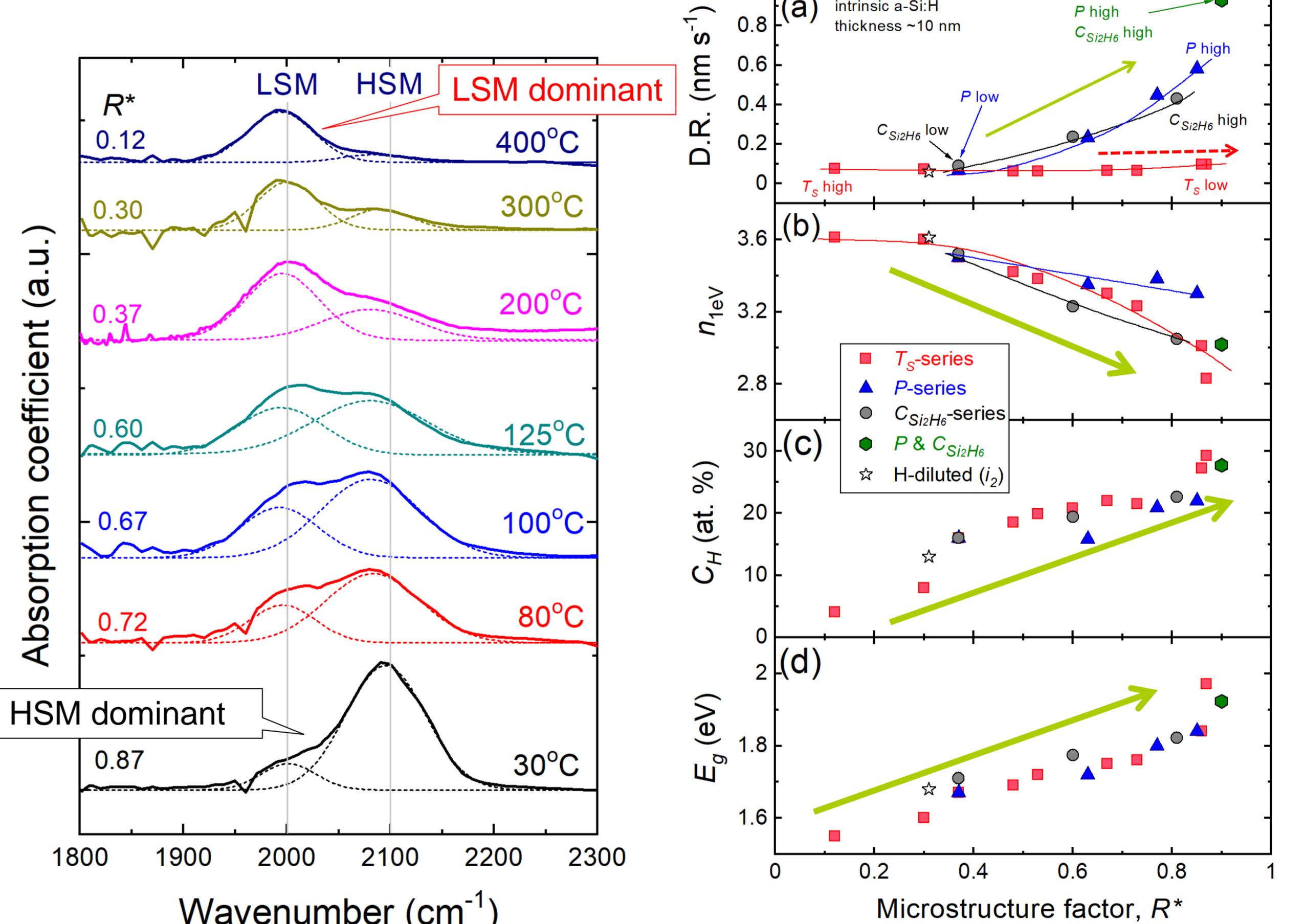
- The V_{OC} , FF, and efficiency are significantly improved by applying i-bilayers.
- The best efficiency is obtained by using i_1 layer with $R^* \sim 0.7$, regardless of the process conditions.



Properties of (i)a-Si:H for interfacial layer [6]

■ Microstructure factor [5]: $R^* = I_{HSM}/(I_{LSM} + I_{HSM})$

- D.R., refractive index (n_{1eV}), hydrogen content (C_H), and bandgap energy (E_g) as well as R^* are controlled widely by varying T_s , P and $C_{\text{Si}_2\text{H}_6}$.



Conclusions

- Material properties of a-Si:H layers can be tuned widely by controlling various PECVD parameters: temperature, pressure, mixing of SiH_4 and Si_2H_6 etc.
- Microstructure factor R^* of interfacial a-Si:H layers is a good measure to improve the surface passivation at a-Si:H/c-Si, regardless of the PECVD parameters.

Acknowledgement

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References

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